FEATURES

- Flexible Operation Modes
  - Constant On-Time Enables Single Stage PFC Implementation
  - Peak Primary Current
- Cascoded MOSFET Configuration
  - Fully Integrated Current Control Without Sense Resistor
  - Fast and Easy Startup
- Discontinuous Conduction Mode or Transition Mode Operation
- Transformer Zero Energy Detection
  - Enables Valley Switching Operation
  - Helps to Achieve High Efficiency and Low EMI
- Open LED Detection
- Advanced Overcurrent Protection
- Output Overvoltage Protection
- Line Surge Ruggedness
- Internal Over-Temperature Protection
- 8-Pin SOIC (D) Package

APPLICATIIONS

- TRIAC Dimmable LED Lighting Designs
- Residential LED Lighting Drivers for Retrofit A19 (E27/26, E14), PAR30/38, GU10, MR16, BR
- Drivers for Down and Architectural Wall Sconces, Pathway and Overhead Lighting
- Commercial Troffers and Downlights

DESCRIPTION

The TPS92210 is a natural power factor correction (PFC) light emitting diode (LED) lighting driver controller with advanced energy features to provide high efficiency control for LED lighting applications.

A PWM modulation algorithm varies both the switching frequency and primary current while maintaining discontinuous or transition mode operation in all regions of operation. The TPS92210 cascode architecture enables low switching loss in the primary side and when combined with the discontinuous conduction mode (DCM) operation ensures that there is no reverse recovery loss in the output rectifier. These innovations result in efficiency, reliability or system cost improvements over a conventional flyback architecture.

The TPS92210 offers a predictable maximum power threshold and a timed response to an overload, allowing safe handling of surge power requirements. The overload fault response is user-programmed for retry or latch mode. Additional protection features include open-LED detection by output overvoltage protection and thermal shutdown.

The TPS92210 is offered in the 8-pin SOIC (D) package. Operating junction temperature range is −40°C to 125°C.
This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

**ORDERING INFORMATION**

<table>
<thead>
<tr>
<th>OPERATING TEMPERATURE RANGE, $T_A$</th>
<th>PACKAGE</th>
<th>ORDERABLE DEVICE NUMBER</th>
<th>PINS</th>
<th>TRANSPORT MEDIA</th>
<th>QUANTITY</th>
</tr>
</thead>
<tbody>
<tr>
<td>$-40^\circ C$ to $125^\circ C$</td>
<td>SOIC</td>
<td>TPS92210DR</td>
<td>8</td>
<td>Tape and Reel</td>
<td>2500</td>
</tr>
<tr>
<td></td>
<td></td>
<td>TPS92210D</td>
<td></td>
<td>Tube</td>
<td>75</td>
</tr>
</tbody>
</table>

**ABSOLUTE MAXIMUM RATINGS**

All voltages are with respect to GND, $-40^\circ C < T_J = T_A < 125^\circ C$, all currents are positive into and negative out of the specified terminal (unless otherwise noted)

<table>
<thead>
<tr>
<th>VALUE</th>
<th>UNIT</th>
<th>MIN</th>
<th>MAX</th>
</tr>
</thead>
<tbody>
<tr>
<td>VDD</td>
<td>V</td>
<td>-0.5</td>
<td>25</td>
</tr>
<tr>
<td>DRN, during conduction</td>
<td></td>
<td>-0.5</td>
<td>2.0</td>
</tr>
<tr>
<td>DRN, during non-conduction</td>
<td></td>
<td></td>
<td>20</td>
</tr>
<tr>
<td>VCG(2)</td>
<td>V</td>
<td>-0.5</td>
<td>16</td>
</tr>
<tr>
<td>TZE, OTM, PCL(3)</td>
<td></td>
<td>-0.5</td>
<td>7</td>
</tr>
<tr>
<td>FB(3)</td>
<td></td>
<td>-0.5</td>
<td>1.0</td>
</tr>
<tr>
<td>VDD – VCG</td>
<td></td>
<td>-7</td>
<td>10</td>
</tr>
<tr>
<td>Continuous input current $I_{VCG}$</td>
<td>mA</td>
<td>10</td>
<td></td>
</tr>
<tr>
<td>Input current range $I_{TZE}, I_{OTM}, I_{PCL}, I_{FB}$</td>
<td>mA</td>
<td>-3</td>
<td>1</td>
</tr>
<tr>
<td>Output current DRN</td>
<td>A</td>
<td>-4</td>
<td></td>
</tr>
<tr>
<td>DRN, pulsed 200ns, 2% duty cycle</td>
<td></td>
<td>-6</td>
<td>1.5</td>
</tr>
<tr>
<td>Operating junction temperature $T_J$</td>
<td>°C</td>
<td>-40</td>
<td>150</td>
</tr>
<tr>
<td>Storage temperature range $T_{stg}$</td>
<td>°C</td>
<td>-65</td>
<td>150</td>
</tr>
<tr>
<td>Lead temperature Soldering, 10 s</td>
<td>°C</td>
<td></td>
<td>260</td>
</tr>
</tbody>
</table>

(1) These are stress ratings only. Stress beyond these limits may cause permanent damage to the device. Functional operation of the device at these or any conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute maximum rated conditions for extended periods of time may affect device reliability.

(2) Voltage on VCG is internally clamped. The clamp level varies with operating conditions. In normal use, VCG is current fed with the voltage internally limited.

(3) In normal use, pins OTM, PCL, TZE, and FB are connected to resistors to GND and internally limited in voltage swing.
THERMAL INFORMATION

<table>
<thead>
<tr>
<th>THERMAL METRIC(1)</th>
<th>TPS92210</th>
<th>UNITS</th>
</tr>
</thead>
<tbody>
<tr>
<td>θJA  Junction-to-ambient thermal resistance(2)</td>
<td>117.5</td>
<td>D</td>
</tr>
<tr>
<td>θJCtop Junction-to-case (top) thermal resistance(3)</td>
<td>63.7</td>
<td>JCtop</td>
</tr>
<tr>
<td>θJB  Junction-to-board thermal resistance(4)</td>
<td>57.8</td>
<td>JB</td>
</tr>
<tr>
<td>ψJT Junction-to-top characterization parameter(5)</td>
<td>15.3</td>
<td>JT</td>
</tr>
<tr>
<td>ψJB Junction-to-board characterization parameter(6)</td>
<td>57.3</td>
<td>JB</td>
</tr>
<tr>
<td>θJCbot Junction-to-case (bottom) thermal resistance(7)</td>
<td>n/a</td>
<td></td>
</tr>
</tbody>
</table>

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
(4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
(5) The junction-to-top characterization parameter, ψJT, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θJA, using a procedure described in JESD51-2a (sections 6 and 7).
(6) The junction-to-board characterization parameter, ψJB, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θJB, using a procedure described in JESD51-2a (sections 6 and 7).
(7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

RECOMMENDED OPERATING CONDITIONS

Unless otherwise noted, all voltages are with respect to GND, –40°C < Tj = Ta < 125°C. Components reference Figure 17.

<table>
<thead>
<tr>
<th></th>
<th>MIN</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>VDD Input voltage</td>
<td>9</td>
<td>20</td>
<td>V</td>
</tr>
<tr>
<td>VCG Input voltage from low-impedance source</td>
<td>9</td>
<td>13</td>
<td></td>
</tr>
<tr>
<td>IVCG Input current from a high-impedance source</td>
<td>10</td>
<td>2000</td>
<td>μA</td>
</tr>
<tr>
<td>ROHM Resistor to GND Shutdown/retry mode</td>
<td>25</td>
<td>100</td>
<td>kΩ</td>
</tr>
<tr>
<td></td>
<td>Latch-off mode</td>
<td>150</td>
<td>750</td>
</tr>
<tr>
<td>RPEC Resistor to GND</td>
<td>24.3</td>
<td>100</td>
<td>kΩ</td>
</tr>
<tr>
<td>Raux Resistor to auxiliary winding</td>
<td>50</td>
<td>200</td>
<td>kΩ</td>
</tr>
<tr>
<td>CVCG VCG capacitor</td>
<td>33</td>
<td>200</td>
<td>nF</td>
</tr>
<tr>
<td>CBP VDD bypass capacitor, ceramic</td>
<td>0.1</td>
<td>1.0</td>
<td>μF</td>
</tr>
</tbody>
</table>

ELECTROSTATIC DISCHARGE (ESD) PROTECTION

<table>
<thead>
<tr>
<th></th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>ESD Rating, Human Body Model (HBM)</td>
<td>1.5</td>
<td>kV</td>
</tr>
<tr>
<td>ESD Rating, Charged Device Model (CDM)</td>
<td>500</td>
<td>V</td>
</tr>
</tbody>
</table>
### ELECTRICAL CHARACTERISTICS

Unless otherwise stated: $V_{DD} = 12$ V, $V_{VCG} = 12$ V, $V_{TZE} = 1$ V, $I_{FB} = 10$ μA, GND = 0 V, a 0.1-μF capacitor exists between VDD and GND, a 0.1-μF capacitor exists between VCG and GND, $R_{PCL} = 33.2$ kΩ, $R_{OTM} = 380$ kΩ, $-40^\circ$C < $T_J$ < $+125^\circ$C, $T_J = T_A$.

#### PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNITS
--- | --- | --- | --- | --- | ---
$V_{CG(OPERATING)}$ | VCG Voltage, Operating | $V_{DD} = 14$ V, $I_{VCG} = 2.0$ mA | 13 | 14 | 15 | V
$V_{CG(DISABLED)}$ | VCG Voltage, PWM Disabled | $V_{DD} = 12$ V, $I_{VCG} = 15$ μA, $I_{FB} = 350$ μA | 15 | 16 | 17 | V
ΔVCG | Rise in VCG Clamping Voltage During UVLO, LPM, or Fault | $V_{CG(DISABLED)} - V_{CG(OPERATING)}$ | 1.75 | 2 | 2.15 | V
$I_{VCG(SREG)}$ | VCG Shunt Regulator Current | $V_{CG} = (V_{CG(DISABLED)} - 100$ mV), $V_{DD} = 12$ V | 6 | 10 | μA
ΔVCG(SREG) | VCG Shunt Load Regulation | $10$ μA $I_{VCG}$ $5$ mA, $I_{FB} = 350$ μA | 125 | 200 | mV
$V_{CG(LREG)}$ | VCG LDO Regulation Voltage | $V_{DD} = 20$ V, $I_{VCG} = -2$ mA | 13 | 2 | 2.5 | V
$V_{DD(UVLO)}$ | UVLO Turn-on Threshold | 9.7 | 10.2 | 10.7 | V
$V_{DD(LPM)}$ | UVLO Turn-off Threshold | 7.55 | 8 | 8.5 | V
ΔVDD(UVLO) | UVLO Hysteresis | 1.9 | 2.2 | 2.5 | V
$I_{VDD(OPERATING)}$ | Operating Current | $V_{DD} = 20$ V | 2.5 | 3 | 3.7 | mA
$I_{VDD(LPM)}$ | Idle Current Between Bursts | $I_{FB} = 350$ μA | 550 | 900 | μA
$I_{VDD(UVLO)}$ | Current for $V_{DD} <$ UVLO | $V_{DD} = V_{DD(UVLO)} - 100$ mV, increasing | 225 | 300 | μA
$R_{ON(LVDD)}$ | VDD Switch on Resistance, DRN to VDD | $V_{CG} = 12$ V, $V_{DD} = 7$ V, $I_{DRN} = 50$ mA | 4 | 10 | | Ω
$V_{DD(FAULT RESET)}$ | VDD for Fault Latch Reset | 5.6 | 6 | 6.4 | V

### MODULATION

$I_{SW(HF)}$ (1) | Minimum switching period, frequency modulation (FM) mode | $I_{FB} = 0$ μA, (1) | 7.125 | 7.5 | 7.875 | μs
$I_{SW(LF)}$ (1) | Maximum switching period, reached at end of frequency modulation (FM) range | $I_{FB} = I_{FB, CNR3} - 20$ μA (1) | 31 | 34 | 38 | μs
$I_{DRN(pk, max)}$ | Maximum peak driver current over amplitude modulation (AM) range | $I_{FB} = 0$ μA, $R_{PCL} = 33.2$ kΩ | 2.85 | 3 | 3.15 | A
$I_{DRN(pk, min)}$ | Minimum peak driver current reached at end of AM modulation range | $I_{FB} = 0$ μA, $R_{PCL} = 100$ kΩ | 0.8 | 0.9 | 1 | A
$K_p$ | Maximum power constant | $I_{DRN(pk, min)} = 3$ A | 0.54 | 0.6 | 0.66 | W/μH
$I_{DRN(pk, abs,min)}$ | Minimum peak driver independent of $R_{PCL}$ or AM control | $R_{PCL} = OPEN$ | 0.3 | 0.45 | 0.6 | A
$I_{BLANK(LIM)}$ | Leading edge current limit blanking time | $I_{FB} = 0$ μA, $R_{PCL} = 100$ kΩ, 1.2-A pull-up on DRN | 220 | | ns
$V_{PCL}$ | PCL Voltage | $I_{FB} = 0$ μA | 2.94 | 3 | 3.06 | V
$I_{FB, CNR3}$ (2) | $I_{FB}$ range for FM modulation | $I_{FB}$ increasing, $I_{SW} = I_{SW(LF)}$, and $I_{DRN(PCL, min)} = I_{DRN(PCL, max)}$ | 145 | 165 | 195 | μA
$I_{FB, CNR2} - I_{FB, CNR1}$ (2) | $I_{FB}$ range for AM modulation | $I_{SW} = I_{SW(LF)}, I_{DRN, PK}$ ranges from $I_{DRN(PK, max)}$ to $I_{DRN(PK, min)}$ | 35 | 45 | 65 | μA
$I_{FB, LPM-HYST}$ (2) | $I_{FB}$ hysteresis during LPM modulation to enter burst on and off states | $I_{FB}$ increasing until PWM action is disabled entering a burst-off state | 45 | 70 | 90 | μA
$FB$ | Voltage of FB | $I_{FB} = 10$ μA | 0.34 | 0.7 | 0.84 | V

(1) $I_{SW}$ sets a minimum switching period. Following the starting edge of a PWM on time, under normal conditions, the next on time is initiated following the first valley switching at $T_{ZE}$ after $I_{SW}$. The value of $I_{SW}$ is modulated by $I_{FB}$ between a minimum of $I_{SW(HF)}$ and a maximum of $I_{SW(LF)}$. In normal operation, $I_{SW(HF)}$ sets the maximum operating frequency of the power supply and $I_{SW(LF)}$ sets the minimum operating frequency of the power supply.

(2) Refer to Figure 24.
ELECTRICAL CHARACTERISTICS (continued)

Unless otherwise stated: \( V_{\text{DD}} = 12 \, \text{V}, V_{\text{VCG}} = 12 \, \text{V}, V_{\text{TZE}} = 1 \, \text{V}, I_{\text{FB}} = 10 \, \mu\text{A}, GND = 0 \, \text{V}, \) a 0.1-\( \mu\text{F} \) capacitor exists between \( V_{\text{DD}} \) and GND, a 0.1-\( \mu\text{F} \) capacitor exists between \( V_{\text{VCG}} \) and GND, \( R_{\text{PCL}} = 33.2 \, \text{k} \Omega, R_{\text{OTM}} = 380 \, \text{k} \Omega, -40^\circ \text{C} < T_{\text{A}} < +125^\circ \text{C}, T_{\text{J}} = T_{\text{A}} \)

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>TEST CONDITIONS</th>
<th>MIN</th>
<th>TYP</th>
<th>MAX</th>
<th>UNITS</th>
</tr>
</thead>
<tbody>
<tr>
<td>TZE(TH)</td>
<td>TZE high to low generates switching period ( t_{\text{SW}} ) has expired</td>
<td>5</td>
<td>20</td>
<td>50</td>
<td>mV</td>
</tr>
<tr>
<td>TZE(LAMP)</td>
<td>TZE low clamp voltage ( I_{\text{TZE}} = -10 , \mu\text{A} )</td>
<td>-220</td>
<td>-160</td>
<td>-100</td>
<td>mV</td>
</tr>
<tr>
<td>TZE(START)</td>
<td>TZE voltage threshold to enable the internal start timer</td>
<td>0.1</td>
<td>0.15</td>
<td>0.2</td>
<td>V</td>
</tr>
<tr>
<td>t(_{\text{CLYITZ2D}})</td>
<td>Delay from zero crossing to Driver turn-on with previous zero current detected</td>
<td>150</td>
<td></td>
<td></td>
<td>ns</td>
</tr>
<tr>
<td>t(_{\text{WAIT(TZE)}})</td>
<td>Wait time for zero energy detection</td>
<td>2</td>
<td>2.4</td>
<td>2.8</td>
<td>( \mu\text{s} )</td>
</tr>
<tr>
<td>t(_{\text{ST}})</td>
<td>Starter time-out period</td>
<td>150</td>
<td>240</td>
<td>300</td>
<td>( \mu\text{s} )</td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>DRIVER</th>
<th>( R_{\text{DS(on)(DRN)}} )</th>
<th>Driver on-resistance ( I_{\text{DRN}} = 4.0 , \text{A} )</th>
<th>90</th>
<th>190</th>
<th>m( \Omega )</th>
</tr>
</thead>
<tbody>
<tr>
<td></td>
<td>( I_{\text{DRN(OFF)}} )</td>
<td>Driver off-leakage current ( I_{\text{DRN}} = 12 , \text{V} )</td>
<td>1.5</td>
<td>20</td>
<td>( \mu\text{A} )</td>
</tr>
<tr>
<td>R(_{\text{DS(on)(HSDRV)}})</td>
<td>HS Driver Current = 50 mA</td>
<td>6</td>
<td>11</td>
<td></td>
<td>( \Omega )</td>
</tr>
<tr>
<td></td>
<td>( I_{\text{TZE(bias)}} )</td>
<td>TZE Input bias current ( V_{\text{TZE}} = 5 , \text{V} )</td>
<td>-0.1</td>
<td>-0.1</td>
<td>( \mu\text{A} )</td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>OVERVOLTAGE FAULT</th>
<th>( T_{\text{ZE(OVP)}} )</th>
<th>Overvoltage fault threshold at TZE Fault latch set</th>
<th>4.85</th>
<th>5</th>
<th>5.15</th>
<th>V</th>
</tr>
</thead>
<tbody>
<tr>
<td>( t_{\text{BLANK,OVP}} )</td>
<td>TZE blanking and OVP sample time from the turn-off edge of DRN</td>
<td>0.6</td>
<td>1</td>
<td>1.7</td>
<td>( \mu\text{s} )</td>
<td></td>
</tr>
<tr>
<td>( t_{\text{ZE(INI)}} )</td>
<td>TZE Input bias current ( V_{\text{TZE}} = 5 , \text{V} )</td>
<td>-0.1</td>
<td>-0.1</td>
<td></td>
<td>( \mu\text{A} )</td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>OVERLOAD FAULT</th>
<th>( t_{\text{FB(OL)}} )</th>
<th>Current to trigger overload delay timer</th>
<th>0</th>
<th>1.5</th>
<th>3</th>
<th>( \mu\text{A} )</th>
</tr>
</thead>
<tbody>
<tr>
<td>( t_{\text{L}} )</td>
<td>Delay to overload fault ( I_{\text{FB}} = 0 , \text{A continuously} )</td>
<td>200</td>
<td>250</td>
<td>300</td>
<td>ms</td>
<td></td>
</tr>
<tr>
<td>( t_{\text{RETRY}} )</td>
<td>Retry delay in retry mode or after shutdown command ( R_{\text{OTM}} = 76 , \text{k} \Omega )</td>
<td>750</td>
<td></td>
<td></td>
<td>ms</td>
<td></td>
</tr>
<tr>
<td>( R_{\text{OTM(TH)}} )</td>
<td>Boundary ( R_{\text{OTM}} ) between latch-off and retry modes</td>
<td>See (3)</td>
<td>100</td>
<td>120</td>
<td>150</td>
<td>k( \Omega )</td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>SHUTDOWN THRESHOLD</th>
<th>( V_{\text{OTM(SR)}} )</th>
<th>Shutdown/retry threshold ( OTM ) high to low</th>
<th>0.7</th>
<th>1</th>
<th>1.3</th>
<th>V</th>
</tr>
</thead>
<tbody>
<tr>
<td>( I_{\text{OTM}} )</td>
<td>OTM current when OTM is pulled low ( V_{\text{OTM}} = V_{\text{OTM(SR)}} )</td>
<td>-600</td>
<td>-450</td>
<td>-300</td>
<td>( \mu\text{A} )</td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>MAXIMUM ON TIME</th>
<th>( t_{\text{OTM}} )</th>
<th>Latch-off ( R_{\text{OTM}} = 383 , \text{k} \Omega )</th>
<th>3.43</th>
<th>3.83</th>
<th>4.23</th>
<th>( \mu\text{s} )</th>
</tr>
</thead>
<tbody>
<tr>
<td></td>
<td>Shutdown/retry ( R_{\text{OTM}} = 76 , \text{k} \Omega )</td>
<td>3.4</td>
<td>3.8</td>
<td>4.2</td>
<td>( \mu\text{s} )</td>
<td></td>
</tr>
<tr>
<td></td>
<td>OTM voltage ( V_{\text{OTM}} )</td>
<td>2.7</td>
<td>3</td>
<td>3.3</td>
<td>V</td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>THERMAL SHUTDOWN</th>
<th>( T_{\text{SS}} )</th>
<th>Shutdown temperature ( T_{\text{J}} ) temperature rising (4)</th>
<th>165</th>
<th></th>
<th></th>
<th>( ^\circ\text{C} )</th>
</tr>
</thead>
<tbody>
<tr>
<td></td>
<td>( T_{\text{SD,HTS}} )</td>
<td>Hysteresis ( T_{\text{J}} ) temperature falling, degrees below ( T_{\text{SS}} ) (4)</td>
<td>15</td>
<td></td>
<td></td>
<td>( ^\circ\text{C} )</td>
</tr>
</tbody>
</table>

(3) A latch-off or a shutdown/retry fault response to a sustained overload is selected by the range of \( R_{\text{OTM}} \). To select the latch-off mode, \( R_{\text{OTM}} \) should be greater than 150 \( \text{k} \Omega \) and \( I_{\text{OTM}} \) is given by \( R_{\text{OTM}} \times (1.0 \times 10^{-11}) \). To select the shutdown/retry mode, \( R_{\text{OTM}} \) should be less than 100 \( \text{k} \Omega \) and \( I_{\text{OTM}} \) is given by \( R_{\text{OTM}} \times (5.0 \times 10^{-11}) \).

(4) Thermal shutdown occurs at temperatures higher than the normal operating range. Device performance at or near thermal shutdown temperature is not specified or assured.
**DEVICE INFORMATION**

**Functional Block Diagram**

- **VDD**: 8
- **FB**: 1
- **TZE**: 2
- **OTM**: 4
- **PCL**: 3
- **VCG**: 5
- **DRN**: 6
- **GND**: 7

- **Feedback Processing**: 
  - $I_{FB} < 210 \mu A$
  - $I_{FB} = 0$
  - $I_{FB} > 210 \mu A$

- **Low-Power Mode**

- **Transformer Zero Energy Detect**

- **Output Voltage Sense**

- **On-Time Modulation and Fault Response Control**

- **Fault Timing & Control**
  - $V_{GATE}$
  - $V_{VDD}$
  - $t_{SW}$
  - $I_{FB}$

- **Fault Latch Reset**

- **Thermal Shutdown**

- **Shutdown and Restart**

- **Latch or Retry**

- **UVLO Reset**

- **Bulk Discharge**

- **HS Drive**

- **Driver**

- **Enable PWM**

- **Driver**

- **Enable PWM**

- **1 V**

- **7.5 k\Omega**

- **TPS92210**
PIN CONFIGURATION

<table>
<thead>
<tr>
<th>TERMINAL</th>
<th>I/O</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>DRN 6</td>
<td>O</td>
<td>The DRN pin is the drain of the internal low voltage power MOSFET of the TPS92210 and carries the peak primary inductor current, I_{PEAK(pri)}. Connect this pin to the source of the external cascode power MOSFET. A schottky diode between DRN and VDD is used to provide initial bias at startup.</td>
</tr>
<tr>
<td>FB 1</td>
<td>I</td>
<td>The FB pin is regulated at 0.7 V and only detects current input (FB current, I_{FB}) which commands the operating mode of TPS92210. For peak-current mode control, this pin is connected to the emitter of the feedback opto coupler. In constant on-time control, the minimum switching period is programmed by forcing a constant current into this pin.</td>
</tr>
<tr>
<td>GND 7</td>
<td>—</td>
<td>This GND pin is the current return terminal for both the analog and power signals in the TPS92210. This terminal carries the full drain current, I_{DRN}, which is equal to the peak primary current, I_{PEAK(pri)}, in addition to the bias supply current (I_{VDD}), and the gate voltage current (I_{VCG}).</td>
</tr>
<tr>
<td>OTM 4</td>
<td>I</td>
<td>The OTM pin is internally regulated at 3 V and used to program the on-time of the cascode (flyback) switch by connecting a resistor (R_{OTM}) from this pin to the quiet return of GND. The collector of the opto-coupler is connected to this pin for constant-on time control. The range of impedance connected at this pin determines the system fault response (latch-off or shutdown/retry) to overload and brownout fault conditions. An external shutdown/retry response can be initiated by pulling this pin low below 1 V.</td>
</tr>
<tr>
<td>PCL 3</td>
<td>I</td>
<td>The PCL pin programs the peak primary inductor current that is reached each switching cycle. The primary current is sensed with the R_{DS(on)} of the internal MOSFET and is programmed by setting a threshold by connecting a low power resistor from this pin to the quiet return of GND.</td>
</tr>
<tr>
<td>TZE 2</td>
<td>I</td>
<td>A resistive divider between the primary-side auxiliary winding and this pin is used to detect when the transformer is demagnetized resulting in transformer zero energy. The ratio of the resistive divider at this pin can also be used to program the output overvoltage protection (OVP) feature.</td>
</tr>
<tr>
<td>VCG 5</td>
<td>—</td>
<td>The VCG pin provides the bias voltage for the gate of the cascode MOSFET. Place a 0.1-µF ceramic capacitor between VCG and GND, as close as possible to the high-voltage MOSFET. This pin also provides start-up bias through a resistor R_SU, which is connected between this pin and the bulk voltage.</td>
</tr>
<tr>
<td>VDD 8</td>
<td>—</td>
<td>VDD is the bias supply pin for the TPS92210. It can be derived from an external source, or an auxiliary winding. Place a 0.1-µF ceramic capacitor between VDD and GND, as close to the device as possible. This pin also enables and disables the general functions of the TPS92210 using the UVLO feature.</td>
</tr>
</tbody>
</table>
TYPICAL CHARACTERISTICS

Unless otherwise stated: $V_{\text{VDD}} = 12 \text{ V}$, $V_{\text{VCG}} = 12 \text{ V}$, $V_{\text{TZE}} = 1 \text{ V}$, $I_{\text{FB}} = 10 \mu\text{A}$, $\text{GND} = 0 \text{ V}$, a 0.1-µF capacitor tied between VDD and GND, a 0.1-µF capacitor tied between VCG and GND, $R_{\text{PCL}} = 33.2 \text{ kΩ}$, $R_{\text{OTM}} = 380 \text{ kΩ}$, $-40^\circ \text{C} < T_A < +125^\circ \text{C}$, $T_J = T_A$

BIAS SUPPLY CURRENT

$\text{V}_{\text{VDD}}$ – Bias Supply Voltage – V

Figure 1.

BIAS SUPPLY CURRENT

$\text{V}_{\text{VDD}}$ – Bias Supply Voltage – V

Figure 2.

BIAS SUPPLY CURRENT

$T_J$ – Junction Temperature – °C

Figure 3.

OPERATIONAL $I_{\text{VDD}}$ – BIAS CURRENT

$V_{\text{VDD}}$ – Bias Voltage – V

Figure 4.
TYPICAL CHARACTERISTICS (continued)

Unless otherwise stated: \( V_{\text{DD}} = 12 \, \text{V} \), \( V_{\text{CG}} = 12 \, \text{V} \), \( V_{\text{Z}E} = 1 \, \text{V} \), \( I_{\text{FB}} = 10 \, \mu\text{A} \), \( GND = 0 \, \text{V} \), a 0.1\( \mu \text{F} \) capacitor tied between VDD and GND, a 0.1\( \mu \text{F} \) capacitor tied between VCG and GND, \( R_{\text{PCL}} = 33.2 \, \text{k}\Omega \), \( R_{\text{OTM}} = 380 \, \text{k}\Omega \), \(-40^\circ \text{C} < T_A < +125^\circ \text{C} \), \( T_J = T_A \).

### OSCILLATOR FREQUENCY vs FEEDBACK CURRENT

- \( T_J = 125^\circ \text{C} \) and \( T_J = 25^\circ \text{C} \)
- Junction Temperature \( (^\circ \text{C}) \):
  - 40
  - 25
  - 125

### MINIMUM SWITCHING PERIOD vs TEMPERATURE

- 7.0
- 7.2
- 7.4
- 7.6
- 7.8
- 8.0
- \( T_J = -40^\circ \text{C} \)

### SWITCHING PERIOD vs AMBIENT TEMPERATURE

- 31
- 32
- 33
- 34
- 35
- 36
- 37
- 38

### PEAK DRN CURRENT vs FEEDBACK CURRENT

- 0
- 0.5
- 1.0
- 1.5
- 2.0
- 2.5
- 3.0
- 3.5

**Figure 5.**

**Figure 6.**

**Figure 7.**

**Figure 8.**
TYPICAL CHARACTERISTICS (continued)

Unless otherwise stated: \( V_{\text{DD}} = 12 \, \text{V}, V_{\text{CG}} = 12 \, \text{V}, V_{\text{TZE}} = 1 \, \text{V}, I_{\text{FB}} = 10 \, \mu \text{A}, \)  GND = 0 V, a 0.1-µF capacitor tied between VDD and GND, a 0.1-µF capacitor tied between VCG and GND, \( R_{\text{PCL}} = 33.2 \, k\Omega, \) \( R_{\text{OTM}} = 380 \, k\Omega, \) \(-40^\circ \text{C} < T_A < +125^\circ \text{C}, \) \( T_J = T_A. \)

**Figure 9.**

- Peak DRN Current vs Transconductance (1/\( R_{\text{PCL}} \))

**Figure 10.**

- Peak DRN Current vs Ambient Temperature

**Figure 11.**

- On Time vs On-Time Modulation Resistance

**Figure 12.**

- On Time vs Junction Temperature

Avoid Operation Here

Best Results

\( 24.3 \, k\Omega < R_{\text{PCL}} < 100 \, k\Omega \)

\( I_{\text{DRN(pk)}} \) – Peak DRN Current – A

\( TA \) – Ambient Temperature – °C

\( R_{\text{PCL}} \) – On-Time Modulation Resistance – kΩ

\( R_{\text{OTM}} \) – Constant On-Time – µS

\( T_J \) – Junction Temperature – °C
TYPICAL CHARACTERISTICS (continued)

Unless otherwise stated: $V_{\text{VDD}} = 12$ V, $V_{\text{VCG}} = 12$ V, $V_{\text{ZEN}} = 1$ V, $I_{\text{FB}} = 10$ µA, $GND = 0$ V, a 0.1µF capacitor tied between VDD and GND, a 0.1-µF capacitor tied between VCG and GND, $R_{\text{PCL}} = 33.2$ kΩ, $R_{\text{OTM}} = 380$ kΩ, $-40^\circ \text{C} < T_A < +125^\circ \text{C}$, $T_J = T_A$

LOW VOLTAGE MOSFET $R_{\text{DS(on)}}$

AMBIENT TEMPERATURE

$R_{\text{DS(on)}}$ – On-Time Resistance – mΩ

$T_A$ – Ambient Temperature – °C

Figure 13.

POWER DISSIPATION

$P_{\text{Diss}}$ – Power Dissipation – W

$T_B$ – Board Temperature – °C

Figure 15.

SAFE OPERATING AREA

vs

BOARD TEMPERATURE

$P_{\text{Diss}}$ – Power Dissipation – W

$T_A$ – Ambient Temperature – °C

Figure 14.

THERMAL COEFFICIENT – $\theta_{JB}$

vs

POWER DISSIPATION

$\theta_{JB}$ – Thermal Coefficient – °C/W

$P_{\text{Diss}}$ – Power Dissipation – W

Figure 16.
Figure 17. Typical Application
DETAILED DESCRIPTION

BIAS AND START-UP

The TPS92210 controls the turn-ON and turn-OFF of the flyback switch through its source by using the cascode configuration. The cascode configuration is also used to provide the initial bias during start-up. The cascode architecture utilizes a low voltage switch whose drain, namely the DRN pin, is connected to the source of the high voltage MOSFET (HV MOSFET). The gate of the HV MOSFET is held at a constant DC voltage using the VCG pin. The TPS92210 cascode based HVMOSFET drive architecture is shown in Figure 18.

Figure 18. Cascoded Architecture

The start-up bias uses a low-level bleed current from either the AC line or the rectified and filtered AC line through the startup resistor (R_{SU}). The bleed current off the line (approximately 6 µA) charges a small VCG capacitor and raises the voltage at the HVMOSFET gate. The HVMOSFET acts as a source follower once the voltage at VCG pin reaches the threshold voltage of the HVMOSFET and raises the DRN pin voltage. During startup the TPS92210 is in undervoltage lockout (UVLO) state with the enable pulse-width modulation (PWM) signal low. This turns on the VDD switch connecting between the DRN pin and the VDD pin, thus allowing \( V_{VDD} \) to also rise with \( V_{VCG} \) minus a threshold voltage of HVMOSFET. An external schottky diode between DRN and VDD is used to steer away potentially high switching currents from flowing through the body diode of the internal VDD switch. The startup current and the operating current paths in the cascode architecture are shown in Figure 19. The VCG pin is shunt regulated at 14 V during normal operation and the regulation level is increased to 16 V during fault, UVLO and startup conditions.
Figure 19. Start-Up and Operating Current in the Cascode Architecture for TPS92210
PRIMARY SIDE CURRENT SENSE

The TPS92210 integrates all of the current sensing and drive, thereby eliminating the need for a current sense resistor. The internal low-voltage switch with typical $R_{\text{DS(on)}}$ of 90 mΩ drives the HVMOSFET through its source and the entire primary current of the transformer flows through this switch and out of the GND pin. The TPS92210 utilizes a current mirror technique to sense and control the primary current. The primary current flowing through the low-voltage switch is scaled and reflected to the PWM comparator where it is compared with the PCL pin current. Thus the peak current reached at each switching cycle is sensed and limited by this comparison.

In peak current-mode control, based on the error signal input at the FB pin, the voltage at the PCL pin and hence the PCL pin current is modulated by TPS92210. The maximum peak primary current is programmed by connecting a low-power resistor from ($R_{\text{PCL}}$) from PCL pin to the quiet return of GND.

$$I_{\text{DRN(pk)}} = \frac{100\,\text{kV}}{R_{\text{PCL}}}$$

At the beginning of each switching cycle a blanking time of approximately 220 ns is applied to the internal current limiter. This allows the low-voltage switch to turn on without false limiting on the leading edge capacitive discharge currents. The drain-gate charge in the HVMOSFET does not affect the turn-off speed because the gate is connected to a low impedance DC source with the help of VCG pin. The cascode configuration enables very fast turn-off of the HVMOSFET and helps to keep switching losses low. Figure 20 illustrates the internal current sensing and control exhibited by programming the resistor at the PCL pin.

![Figure 20. Peak Current Limit (PCL) Pin Details](image-url)
FEEDBACK AND MODULATION

The TPS92210 can be programmed to operate in constant-on time control or in peak-current mode control based on how the error signal is fed back to its modulator.

Constant-On Time Control Using the OTM Pin

The power factor describes how well an AC load corresponds to a pure resistance. A flyback transformer operating in discontinuous conduction mode (DCM) creates a peak primary current described in Equation 2.

\[ I_{PEAK} = \left( \frac{V_{BULK} \times t_{ON}}{L_M} \right) = \left( \frac{V_{BULK}}{\frac{L_M}{t_{ON}}} \right) \]

where

- \( L_M \) is the magnetizing inductance of the flyback transformer
- \( t_{ON} \) is the on-time of the flyback switch
- \( \frac{L_M}{t_{ON}} \) is expressed in units of (\( \mu \)H/s) \( \frac{(V)}{(\Omega)} \) (2)

thus,

\[ I_{PEAK} = \frac{V_{BULK}}{\frac{L_M}{t_{ON}}} \left( \frac{V}{\Omega} \right) \]

(3)

If the on-time is limited to a fixed value, then the peak primary current in the transformer is directly proportional to the bulk supply voltage. Consequently, a flyback operating in DCM with a fixed inductance and fixed on-time behaves much like a pure resistance and exhibits a power factor close to unity when operating with a small bulk capacitance. The TPS92210 can easily be configured for constant on-time control, allowing fixed-frequency, single-stage power factor regulation.

In constant-on time control, the on-time of the primary switch can be programmed by connecting a resistor (R_{OTM}) between the OTM pin and the quiet return of GND. The on-time can be further modulated by connecting the collector of the opto-coupler to the OTM pin through a resistor as shown in Figure 21.
The OTM multi-function pin is also used to program the system response to overload and brownout conditions. Figure 22 shows how the on-time is programmed over the range of between 1.5 µs and 5 µs for either range of programming resistors. The resistor range determines the controller response to a sustained overload fault (to either latch-off or to shutdown/retry) which is the same response for a line-sag, or brown out, condition. The on-time is related to the programmed resistor based on the following equations.

The on-time for latch-off response to overcurrent faults is shown in Equation 4.

\[
R_{\text{OTM}} = t_{\text{OTM}} \times \left(1 \times 10^{11} \frac{\Omega}{s}\right)
\]  

(4)

The on-time for the shutdown/retry response to overcurrent faults is shown in Equation 5.

\[
R_{\text{OTM}} = t_{\text{OTM}} \times \left(2 \times 10^{10} \frac{\Omega}{s}\right)
\]  

(5)

Figure 22. On-time Programming Range and Overload Fault Response Selection

The OTM pin can also be used to externally shutdown the converter by pulling the OTM pin low below \(V_{\text{OTM(SR)}}\) threshold (typically 1 V). The PWM action is disabled and the controller retries after the shutdown/retry delay of 750 ms.
Peak-Current Mode Control Using the FB Pin

In peak-current mode control, the FB pin is used to feed back the output error signal to the internal modulator. In this mode of control, the emitter of the opto-coupler is connected to the FB pin and a resistor ($R_{FB}$) is connected from FB to the quiet return of GND to bleed off the dark current of the opto-coupler. The FB pin detects current input only, and the voltage at this pin is normally 0.7 V. The FB pin interface is outlined in Figure 23.

To Modulators
Low-Power Mode
Overload

IFB

0 A < IFB < 210 μA
IFB > 210 μA
IFB = 0 A

Figure 23. FB Pin Details for Peak-Current Mode Control

The FB current (IFB) commands the TPS92210 to operate the flyback converter in one of the three modes
- Frequency Modulation (FM) mode
- Amplitude Modulation (AM) mode
- Low power mode (LPM)

The converter operates in FM mode with a large power load (23% to 100% the peak regulated power). The peak HVMOSFET current reaches its maximum programmed value and FB current regulates the output voltage by modulating the switching frequency, which is inversely proportional to $t_{SW}$. The switching frequency range is nominally from 30 kHz (23% peak power) to 133 kHz (100% peak power).
The maximum programmable HVMOSFET current, $I_{\text{DRN,PK(max)}}$, is set by the resistor on the PCL pin, as described in Equation 1. The converter operates in AM mode at moderate power levels (2.5% to 23% of the peak regulated power). The FB current regulates the output voltage by modulating the peak HVMOSFET current from 33% to 100% of the maximum programmed value while the switching frequency is fixed at approximately 30 kHz. The TPS92210 modulates the voltage on the PCL pin from 3 V to 1 V to vary the commanded peak current, as shown in Figure 24.

![Figure 24. FB Pin Based Modulation Modes](UDG-09156)

The converter operates in LPM at light load (0% to 2.5% of the peak regulated power). The FB current regulates the output voltage in the Low Power Mode with hysteretic bursts of pulses using FB current thresholds. The peak HVMOSFET current is 33% of the maximum programmed value. The switching frequency within a burst of pulses is approximately 30 kHz. The duration between bursts is regulated by the power supply control dynamics and the FB hysteresis. The TPS92210 reduces internal bias power between bursts in order to conserve energy during light-load and no-load conditions.
TRANSFORMER ZERO ENERGY DETECTION

The TPS92210 ensures that the flyback converter always operates in DCM and initiates a new switching cycle only when the primary transformer has been completely reset or when its energy is zero. The TZE pin is connected through a resistive divider to the primary-side auxiliary winding for zero energy detection. The transformer zero energy is detected by monitoring the current sourced out of the TZE pin when the primary bias winding of the flyback converter is negative with respect to GND. The voltage at this pin is clamped at −160 mV during the negative excursions of the auxiliary winding. A small delay, between 50 ns and 200 ns, can be added with $C_{TZE}$ to align the turn-on of the primary switch with the resonant valley of the primary winding waveform enabling valley switching. Figure 25 shows the waveform on the HVMOSFET drain, the voltage at the TZE pin and the primary current in the transformer. It also illustrates how $C_{TZE}$ delays the voltage at the TZE pin to cause the TPS92210 to switch at the resonant valley.

Figure 25. TZE and HVMOSFET Drain Voltages for Valley Switching

The TPS92210 requires that three conditions are satisfied before it can initiate a new switching cycle.
- The time since the last turn-on edge must be equal to or greater than the time that is requested by the feedback processor as determined by the feedback current, $I_{FB}$.
- The time since the last turn-on edge must be longer than the minimum period that is built into the device (nominally 7.5 µs which equals 133 kHz).
- Immediately following a high-to-low zero crossing of the TZE pin voltage. Or, it has been longer than $t_{\text{WAIT,TZE}}$ since the last zero crossing of the current has been detected

The TZE pin is also used to program the output overvoltage protection or open-LED detection feature. The output voltage is monitored by TPS92210 by sampling the voltage at the auxiliary winding. The voltage is sampled after a fixed delay of 1 µs after the internal low-voltage switch has turned off. This allows the auxiliary winding to be sampled after the bias winding voltage settles from the transient. The output over-voltage threshold is set using the turns ratio of the auxiliary winding to the output secondary and a resistive divider into the TZE pin. The controller latches-off on an open-LED fault and requires a power recycle to reset the fault latch (VDD recycling below fault reset threshold of 6 V). The interface to the TZE pin for zero energy detection and OVP feature is shown in Figure 26.
Figure 26. TZE and Output Overvoltage Detection
### Terminal Components

<table>
<thead>
<tr>
<th>NAME</th>
<th>TERMINAL</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>PCL</td>
<td>3</td>
<td>$R_{\text{PCL}} = 33.2 , \text{k}\Omega \times \left( \frac{(K_P \times L_M)}{P_{\text{IN}}} \right)^{\frac{1}{2}}$</td>
</tr>
<tr>
<td></td>
<td></td>
<td>$I_{\text{DRN(pk)}} = \left( \frac{100 , \text{kV}}{R_{\text{PCL}}} \right)$</td>
</tr>
<tr>
<td></td>
<td></td>
<td>where $K_P = 0.54 , \text{W/}\mu\text{H}$, $L_M$ is the minimum value of primary inductance, $P_{\text{IN}} = P_{\text{OUT}}/\eta$, $\eta = \text{efficiency}$</td>
</tr>
<tr>
<td>DRN</td>
<td>6</td>
<td>$M_1$, power MOSFET with adequate voltage and current ratings, $V_{\text{GS}}$ must have at least 20 V static rating. D1, Schottky diode, rated for at least 30 V, placed between DRN and VDD</td>
</tr>
<tr>
<td>FB</td>
<td>1</td>
<td>$100 , \text{k}\Omega$</td>
</tr>
<tr>
<td>GND</td>
<td>7</td>
<td>Bypass capacitor to VDD, $C_{\text{BP}} = 0.1 , \mu\text{F}$, ceramic</td>
</tr>
<tr>
<td>OTM</td>
<td>4</td>
<td>For Latch-Off response to overcurrent faults: $R_{\text{OTM}} = t_{\text{OTM}} \times \left( 1 \times 10^{11} , \Omega \right)$ s^{-1}</td>
</tr>
<tr>
<td></td>
<td></td>
<td>For shutdown/retry response to overcurrent faults: $R_{\text{OTM}} = t_{\text{OTM}} \times \left( 2 \times 10^{10} , \Omega \right)$ s^{-1}</td>
</tr>
<tr>
<td>VDD</td>
<td>8</td>
<td>$C_{\text{VDD}} = \frac{I_{\text{VDD(LPM)}} \times t_{\text{BURST}}}{\Delta V_{\text{DD(burst)}}}$</td>
</tr>
<tr>
<td></td>
<td></td>
<td>where $\Delta V_{\text{DD(burst)}}$ is the allowed VDD ripple during burst operation, $t_{\text{BURST}}$ is the estimated burst period</td>
</tr>
<tr>
<td></td>
<td></td>
<td>The typical $C_{\text{VDD}}$ value is approximately 48 $\mu$F.</td>
</tr>
<tr>
<td></td>
<td></td>
<td>$D_{\text{BIAS}}$ must have a voltage rating greater than: $V_{\text{DBIAS}} \geq V_{\text{OUT}} \times \left( \frac{N_{\text{PS}}}{N_{\text{PB}}} + \frac{V_{\text{BULK(max)}}}{N_{\text{PB}}} \right)$</td>
</tr>
<tr>
<td></td>
<td></td>
<td>where $V_{\text{DBIAS}}$ is the reverse voltage rating of diode D2, $V_{\text{BULK(max)}}$ is the maximum rectified voltage of $C_{\text{BULK}}$ at the highest line voltage</td>
</tr>
<tr>
<td>VCG</td>
<td>5</td>
<td>$C_{\text{VCG}} = \text{at least } 10 \times \text{CGS of the HVMOSFET, usually } C_{\text{VCG}} = 0.1 , \mu\text{F}$</td>
</tr>
<tr>
<td>TZE</td>
<td>2</td>
<td>$R_{\text{TZE1}} = \left( \frac{V_{\text{OUT}} + V_F}{100 , \mu\text{A}} \right) \times \frac{N_{\text{PS}}}{N_{\text{PB}}}$</td>
</tr>
<tr>
<td></td>
<td></td>
<td>$R_{\text{TZE2}} = \frac{R_{\text{TZE1}} \times \text{TE}<em>{\text{OVP}} \times R</em>{\text{TZE1}}}{\left( V_{\text{OUT(pk)}} \times \frac{N_{\text{PS}}}{N_{\text{PB}}} \right) - \text{TE}_{\text{OVP}}}$</td>
</tr>
<tr>
<td></td>
<td></td>
<td>where $V_{\text{OUT}}$ is the average output voltage of the secondary, $V_F$ is the forward bias voltage of the secondary rectifier, $V_{\text{OUT(pk)}}$ is the desired output overvoltage fault level</td>
</tr>
</tbody>
</table>

(1) Refer to the Electrical Characteristics Table for all constants and measured values, unless otherwise noted.
(2) Refer to Figure 17 for all component locations in the Terminal Components Table.
## REVISION HISTORY

### Changes from Original (JANUARY 2010) to Revision A

<table>
<thead>
<tr>
<th>Change</th>
<th>Page</th>
</tr>
</thead>
<tbody>
<tr>
<td>Changed Corrected Pin 2 name</td>
<td>1</td>
</tr>
<tr>
<td>Changed Corrected Pin 2 name</td>
<td>12</td>
</tr>
<tr>
<td>Changed location of Zener diode in Figure 19</td>
<td>14</td>
</tr>
</tbody>
</table>

### Changes from Revision A (DECEMBER 2010) to Revision B

<table>
<thead>
<tr>
<th>Change</th>
<th>Page</th>
</tr>
</thead>
<tbody>
<tr>
<td>Added clarity to conditions in ELECTRICAL CHARACTERISTICS table</td>
<td>4</td>
</tr>
<tr>
<td>Changed maximum PCL voltage specification from &quot;1.05&quot; to &quot;1.1&quot; in ELECTRICAL CHARACTERISTICS table</td>
<td>4</td>
</tr>
<tr>
<td>Changed minimum I_{FM} range for low power mode (LPM) modulation from &quot;50&quot; to &quot;45&quot; in ELECTRICAL CHARACTERISTICS table</td>
<td>4</td>
</tr>
<tr>
<td>Added clarity to conditions in ELECTRICAL CHARACTERISTICS table</td>
<td>5</td>
</tr>
<tr>
<td>Changed minimum TZE low clamp voltage from &quot;–200&quot; to &quot;–220&quot; in ELECTRICAL CHARACTERISTICS table</td>
<td>5</td>
</tr>
<tr>
<td>Added clarity to FUNCTIONAL BLOCK DIAGRAM</td>
<td>6</td>
</tr>
<tr>
<td>Added clarity to &quot;conditions&quot; statement in TYPICAL CHARACTERISTICS</td>
<td>8</td>
</tr>
<tr>
<td>Added clarity to Figure 23</td>
<td>18</td>
</tr>
<tr>
<td>Added clarity to Figure 24</td>
<td>19</td>
</tr>
</tbody>
</table>
# PACKAGE OPTION ADDENDUM

## PACKAGING INFORMATION

<table>
<thead>
<tr>
<th>Orderable Device</th>
<th>Status (1)</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>Package Qty</th>
<th>Eco Plan (2)</th>
<th>Lead/Ball Finish (6)</th>
<th>MSL Peak Temp (3)</th>
<th>Op Temp (°C)</th>
<th>Device Marking (4/5)</th>
<th>Samples</th>
</tr>
</thead>
<tbody>
<tr>
<td>HPA01125DR</td>
<td>ACTIVE</td>
<td>SOIC</td>
<td>D</td>
<td>8</td>
<td>2500</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 125</td>
<td>92210</td>
<td></td>
</tr>
<tr>
<td>TPS92210D</td>
<td>ACTIVE</td>
<td>SOIC</td>
<td>D</td>
<td>8</td>
<td>75</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 125</td>
<td>92210</td>
<td></td>
</tr>
<tr>
<td>TPS92210DR</td>
<td>ACTIVE</td>
<td>SOIC</td>
<td>D</td>
<td>8</td>
<td>2500</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 125</td>
<td>92210</td>
<td></td>
</tr>
</tbody>
</table>

(1) The marketing status values are defined as follows:
- **ACTIVE**: Product device recommended for new designs.
- **LIFEBUY**: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
- **NRND**: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
- **PREVIEW**: Device has been announced but is not in production. Samples may or may not be available.
- **OBSOLETE**: TI has discontinued the production of the device.

(2) **RoHS**: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
- **RoHS Exempt**: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
- **Green**: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) **MSL, Peak Temp.** - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) **Lead/Ball Finish** - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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**TAPE AND REEL INFORMATION**

### REEL DIMENSIONS

![Reel Diagram](image)

### TAPE DIMENSIONS

- **A0** Dimension designed to accommodate the component width
- **B0** Dimension designed to accommodate the component length
- **K0** Dimension designed to accommodate the component thickness
- **W** Overall width of the carrier tape
- **P1** Pitch between successive cavity centers

### TAPE AND REEL INFORMATION

*All dimensions are nominal*

<table>
<thead>
<tr>
<th>Device</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>SPQ</th>
<th>Reel Diameter (mm)</th>
<th>Reel Width W1 (mm)</th>
<th>A0 (mm)</th>
<th>B0 (mm)</th>
<th>K0 (mm)</th>
<th>P1 (mm)</th>
<th>W (mm)</th>
<th>Pin1 Quadrant</th>
</tr>
</thead>
<tbody>
<tr>
<td>TPS92210DR</td>
<td>SOIC</td>
<td>D</td>
<td>8</td>
<td>2500</td>
<td>330.0</td>
<td>12.4</td>
<td>6.4</td>
<td>5.2</td>
<td>2.1</td>
<td>8.0</td>
<td>12.0</td>
<td>Q1</td>
</tr>
</tbody>
</table>

Pack Materials-Page 1
<table>
<thead>
<tr>
<th>Device</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>SPQ</th>
<th>Length (mm)</th>
<th>Width (mm)</th>
<th>Height (mm)</th>
</tr>
</thead>
<tbody>
<tr>
<td>TPS92210DR</td>
<td>SOIC</td>
<td>D</td>
<td>8</td>
<td>2500</td>
<td>340.5</td>
<td>338.1</td>
<td>20.6</td>
</tr>
</tbody>
</table>

*All dimensions are nominal*
NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.

2. This drawing is subject to change without notice.

3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.

4. This dimension does not include interlead flash.

5. Reference JEDEC registration MS-012, variation AA.
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
EXAMPLE STENCIL DESIGN

SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE 8X

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.
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